

## Supporting Information

# Thermoelectric Energy from Flexible P3HT Films Doped by a Ferric Salt of Triflimide Anions

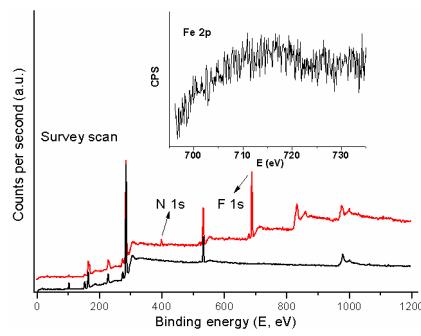
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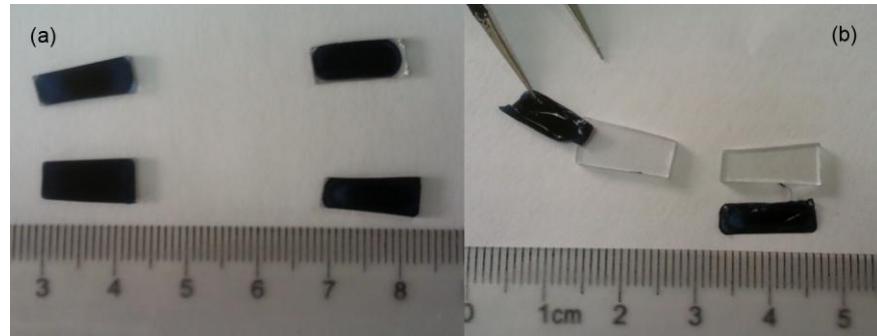
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**Fig. S1** Survey scan of XPS characterization for P3HT films before (black) and after doping (red). The inset shows detail of Fe(2p).



**Fig. S2** P3HT-TFSI films (a) before and (b) after being detached from substrates with tweezers.

**Table S1.** Summary of thermoelectric property of P3HT at room temperature ever reported and obtained in this work.

Matrix	Dopant (solvent)	Electrical conductivity [S cm <sup>-1</sup> ]	Seebeck coefficient [ $\mu\text{V K}^{-1}$ ]	Power factor [ $\mu\text{W m}^{-1}\text{K}^{-2}$ ]
P3HT <sup>1</sup> (film, 1.75 $\mu\text{m}$ )	F4-TCNQ (chlorobenzene)	$3.8 \times 10^{-4}$	400	0.006
P3HT <sup>2</sup> (film, 1 $\mu\text{m}$ )	NOPF <sub>6</sub> (acetonitrile)	2.2	25	0.14
P3HT <sup>3</sup> (film, 15 $\mu\text{m}$ )	FeCl <sub>3</sub> (chloroform)	7	74	3.9
P3HT <sup>4</sup> (film, 5 $\square\mu\text{m}$ )	FeCl <sub>3</sub> (chloroform)	$8.9 \times 10^{-3}$	5400	26
P3HT <sup>a</sup> (film, 0.7 $\square\mu\text{m}$ )	FeCl <sub>3</sub> (nitromethane)	21	30	1.9
P3HT <sup>b</sup> (film, 0.7 $\mu\text{m}$ )	NOPF <sub>6</sub> (acetonitrile)	10	36	1.3

<sup>a,b</sup> Samples doped by dopants ever reported are prepared in this work for comparison. FeCl<sub>3</sub> solution (in nitromethane, 10 mg ml<sup>-1</sup>) and NOPF<sub>6</sub> solution (in acetonitrile, 5 mM) are used and the immersing time was 1.5 and 0.2 hours respectively.

**Table S2.** Carrier density of doped P3HT films extracted from temperature dependence of Seebeck coefficient according to Mott relation or from XPS measurement.

Formula	$\frac{S}{T} = \frac{\pi^2 k_B^2 m^*}{(3\pi^2)^{2/3} \hbar^2  e  n^{2/3}}$	$n = N \cdot \rho$	
Available parameters	Effective mass <sup>5</sup> [m <sup>*</sup> , kg]	1.7 m <sub>e</sub> <sup>a</sup>	Oxidation ratio ( $\rho$ ) <sup>b</sup> Density of states [N, cm <sup>-3</sup> ] <sup>6</sup>
Extracted parameters	Carrier density [n, cm <sup>-3</sup> ]	$1.62 \times 10^{21}$	Carrier density [n, cm <sup>-3</sup> ]
	$\mu = 0.2 \text{ cm}^2 \text{ V}^{-1} \text{s}^{-1}$	51.8	$\mu = 0.2 \text{ cm}^2 \text{ V}^{-1} \text{s}^{-1}$
Electrical conductivity at supposed carrier mobility <sup>c</sup> ( $\sigma$ , S cm <sup>-1</sup> )	$\mu = 0.3 \text{ cm}^2 \text{ V}^{-1} \text{s}^{-1}$	77.7	$\mu = 0.3 \text{ cm}^2 \text{ V}^{-1} \text{s}^{-1}$
	$\mu = 0.35 \text{ cm}^2 \text{ V}^{-1} \text{s}^{-1}$	90.7	$\mu = 0.35 \text{ cm}^2 \text{ V}^{-1} \text{s}^{-1}$

<sup>a</sup> m<sub>e</sub> is the rest mass of electrons; <sup>b</sup> oxidation ratio is defined as unit positive charge per thiophene monomer, determined by XPS as the area ratio of S(2p) peak around 168 eV to that around 164 eV; <sup>c</sup> although the estimated carrier mobility is above most results extracted from measurement in field-effect transistors of P3HT,<sup>7</sup> it is in accord with the mobility range of heavily doped P3HT.<sup>3,8</sup>

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